



FIRST SEMESTER M.Tech. (ME) DEGREE END SEMESTER EXAMINATION

NOV 2017

SUBJECT: ADVANCED DIGITAL VLSI DESIGN (ECE - 5121)

TIME: 3 HOURS

MAX. MARKS: 50

Instructions to candidates

- Answer **ALL** questions.
- Missing data may be suitably assumed.

- 1A. Discuss the various options for pull-up device in an inverter and critically analyse their suitability.
- 1B. What is meant by switch logic and gate logic? Describe and compare them. Also show how a 4:1 mux can be implemented using switch logic that produces un-degraded outputs. (5+5)
- 2A. With the help of a neat circuit diagram explain:
 - i) Pseudo NMOS inverter with its merits and demerits.
 - ii) 2 input NAND gate using BiCMOS logic indicate the function of each transistor.
- 2B. Explain different types of technology scaling. Illustrate the impact of full scaling on the dynamic power dissipation, Drain current and Gate capacitance. (5+5)
- 3A. With the help of neat diagram, explain the process steps involved in patterning of polysilicon.
- 3B. In a CMOS inverter, both NMOS & PMOS transistors have $W=2.0\mu\text{m}$, $L=0.5\mu\text{m}$, process parameters $k = 110 \mu\text{A/V}^2$, V_{DD} and V_{th} are 2.2 V and 0.6V respectively. Calculate the inverter pair delay. Assume that the sheet resistance of N+ diffusion channel is 10kOhm and the electron mobility is $270 \text{ cm}^2/\text{V-sec}$.
- 3C. Implement Boolean function $F = \overline{((A + B + C)D)}$ using CMOS logic and size the transistors for optimum performance. (5+3+2)
- 4A. With the help of neat diagrams explain the operations of electrically alterable and non-electrically alterable semiconductor memories.
- 4B. What is the word line and bit line capacitance in a 64K SRAM (256 X 256, 6 T SRAM), with access transistors of W/L ratio equal to $0.5\mu\text{m}/0.1\mu\text{m}$? The contacts on the bit lines are shared between pairs of cells and have a capacitance of 0.5fF each. The wire capacitance is 0.2 fF/ μm and the cell size is $2\mu\text{m} \times 1.5\mu\text{m}$.
- 4C. List the limitations of 6 T SRAM and indicate remedies for the same. (5+3+2)
- 5A. i) Briefly explain the design rules and compare them.
ii) For the Boolean function $F(ABCD) = ((A.(B+C))+D)$, draw the stick diagram with and with out Euler path method.
- 5B. Define i) Clock skew and ii) Jitter . Also give the details of their cause and remedies.
- 5C. What is meant by di/dt noise? Explain with its impact in VLSI. (5+3+2)